

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240416US0DIV		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Masakazu KANECHIKA, et al.		10618085	
				FILING DATE Herewith 7-14-03		GROUP 2813	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TN	AA	5,444,244	08/95	Kirk et al.			
TN	AB	6,328,902	12/01	Hantschel et al.			
TN	AC	5,844,251	12/98	MacDonald et al.			
TN	AD	5,780,318	07/98	Hirano et al.			
TN	AE	5,587,588	12/96	Kim			
TN	AF	5,910,701	06/99	Takemura			
TN	AG	6,333,598	12/01	Hsu et al.			
TN	AH	6,066,265	05/00	Galvin et al.			
TN	AI	5,367,165	11/94	Toda et al.			
TN	AJ	4,968,585	11/90	Albrecht et al.			
TN	AK	4,933,058	06/90	Bache et al.			
TN	AL	6,201,401	03/01	Hellenmans et al.			
TN	AM	5,295,305	03/94	Hahn et al.			
TN	AN	5,614,663	03/97	Itoh et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
TN	AO	6-163481	06/10/94	Japan (w/English Abstract)			XX
TN	AP	9-260312	10/03/97	Japan (w/English Abstract)			XX
TN	AQ	8-250020	09/27/96	Japan (w/English Abstract)			XX
TN	AR	63-051641	03/04/88	Japan (w/English Abstract)			XX
TN	AS	10-188785	04/08/98	Japan (w/English Abstract, corr. to US 6,036,566)			XX
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
TN	AW	Seigo KANEMARU, et al., "FABRICATION OF METAL-OXIDE-SEMICONDUCTOR FIELD-EFFECT-TRANSISTOR-STRUCTURED SILICON FIELD EMITTERS WITH A POLYSILICON DUAL GATE", Jpn. J. Appl. Phys., Vol. 36, Part 1, No. 12B, December 1997, pages 7736-7740					
TN	AX	Yoshikazu HORI, et al., "NEW SUB-MICRON SIZE Si FIELD EMITTER ARRAYS WITH LOW OPERATION VOLTAGE", technical Report of The Institute of Electronics Information and Communication Engineers, ED94-95, 1994-12, pages 1-8, (w/English Abstract)					
	AY						
	AZ						
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <u>T. NGUYEN</u>					Date Considered <u>5/12/04</u>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
TN	AA	5,232,568	08/93	Parent et al.			
TN	AB	5,497,656	03/96	Kado et al.			
TN	AC	6,285,811	09/01	Aggarwal et al.			
TN	AD	6,132,942	10/00	Woodworth et al.			
TN	AE	6,227,519	05/01	Yagi et al.			
TN	AF	5,992,268	11/99	Decker et al.			
TN	AG	5,967,873	10/99	Rabinowitz			
TN	AH	6,270,950	08/01	Bourdelais et al.			
TN	AI	6,036,566	03/14/00	Baldi et al.			
	AJ						
	AK						
	AL						
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	AN						
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